

<b>Notice of References Cited</b>	Application/Control No. 10/541,689	Applicant(s)/Patent Under Reexamination ANNIC, ETIENNE	
	Examiner SHIH-WEI KRAFT	Art Unit 2194	Page 1 of 1

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*	B	US-6,654,754 B1	11-2003	Knauff et al.	1/1
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**NON-PATENT DOCUMENTS**

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